

CCM Switched-inductor Converter-efficiency Performance across Process Nodes

Luke Milner, *Student Member, IEEE*, and Gabriel A. Rincón-Mora, *Fellow, IEEE*

Georgia Tech Analog, Power, and Energy IC Research

Objective: To assess the impact of process technology on the (efficiency) performance of switched-inductor dc-dc converters.

Abstract: The table below compares the effects of decreasing L_{MIN} (i.e., increasing C_{OX} and therefore increasing K') on the loss mechanisms and resulting peak and full-load efficiencies η_P and η_{FL} of a 10-MHz buck converter in CCM. The comparison does not apply to (a) DCM because conduction losses P_C in DCM contribute less to the total losses and do not relate to I_{OUT} in the same way as in CCM or (b) speed because a lower L_{MIN} could increase f_{oAB} and f_{SW} (under hysteretic control) and therefore reduce output ripple.

Observations: P_C decreases with a lower L_{MIN} because a higher K' decreases R_{DSON} , but not as fast because the breakdown voltage V_{GSS} of a smaller L_{MIN} decreases gate-drive voltage V_{GST} , plus the total resistance includes the interconnecting metal and the inductor's ESR, which do not scale with L_{MIN} . Driver losses P_D decrease with a lower L_{MIN} because, while shoot-through losses P_{ST} increase because K' reduces R_{DSON} , larger gate-charge losses P_{GC} decrease more because reductions in L_{MIN} and transistor widths W overwhelm the rise in C_{OX} . Overlap and quiescent losses P_{OV} and P_Q do not scale with L_{MIN} (if f_{oAB} and f_{SW} remain unchanged).

Conclusions: With optimal W , because both P_C and P_D decrease with a lower L_{MIN} , η_P (which occurs at the edge of DCM) increases by roughly 1.32% for every 50% (i.e., $2\times$) reduction in L_{MIN} at 1.8 V, and less (by 0.85%) at higher voltages (at 3.6 V) because P_Q is higher and losses therefore become a smaller fraction of η_P (which is why η_P is generally higher at higher voltages). A larger (non-optimal) W can improve η_{FL} (e.g., at 2 A), where P_C dominates, by 15% while lowering η_P by less than 2%. Interestingly, the optimal aspect ratio W/L used for each technology and output voltage combination resulted in nearly the same value in all cases.

Technology	0.18 μ m [1]		0.35 μ m [2]		0.6 μ m [3]	
	NMOS	PMOS	NMOS	PMOS	NMOS	PMOS
$k' (\mu C_{OX}/2) (\mu A/V^2)$	171	37	89	33	58	19
$R_{DSON} (2.7V) (k\Omega/sq.)$	-	-	4.6	16	6.6	21
$R_{DSON} (4.2V) (k\Omega/sq.)$	3.3 (@1.8V)	13 (@1.8V)	4.1 (@3.3V)	13 (@3.3V)	5.2	15
$C_{OX} (fF/\mu m^2)$	8.4	8.4	4.5	4.5	2.4	2.4
Nom. Voltage (Thick Ox.)	1.8V (3.3V)	1.8V (3.3V)	3.3V (5V)	3.3V (5V)	5V	5V

Technology	0.18 μ m (A) [1]		0.35 μ m (A) [2]		0.6 μ m (B) [3]		
	Efficiency (E)	P_{OV}	100%	100%	100%	100% (6.2mW at 0.22A)	
P_C (D)		70%	83%	83%	100% (23mW at 0.22A)		
R_{SW} (C)		71%	77%	85%	86%	100% (259m Ω)	100% (559m Ω)
P_D (F)		59%	77%	77%	77%	100% (15.3mW)	
P_{ST} (G)		148%	121%	121%	121%	100% (2.9mW)	
P_{GC}		38%	66%	66%	66%	100% (12.5mW)	
P_Q		100%	100%	100%	100%	100% (4.2mW)	
P_{LEAK}		Neglected		Neglected		Neglected	
Peak (1.8V)		91.50%	90.43%	90.43%	90.43%	89.11%	
(W/L)		3.97E+04	3.40E+04	3.40E+04	3.40E+04	3.27E+04	
Peak (3.3V)	94.80%	94.13%	94.13%	94.13%	93.27%		
(W/L)	4.34E+04	3.60E+04	3.60E+04	3.60E+04	3.40E+04		
Accuracy	Ripple	100%	100%	100%	100%		
	Transient	100%	100%	100%	100%		
Price (H)		MM	MM-HV	MM	MM-HV	MM	
	Die	\$33,500	-	\$8,500	\$9,000	\$2,000	
	Package	\$2,600	-	\$2,600	\$2,600	\$2,600	
	Total	\$36,100	-	\$11,100	\$11,600	\$4,600	

Assumptions:

- The battery voltage (V_{IN}) is assumed to be 4.2V in every case even though additional circuits are needed to protect transistors in the some technologies. R_{DSON} is calculated using realistic gate-drive (e.g. 1.8V for TSMC 0.18 μ m).
- Losses and resistance estimates are normalized to the values for 0.6 μ m.
- Includes 100m Ω for metal in addition to the resistance of the silicon.
- Given for the value of I_{OUT} where efficiency is maximum. (Not the same for every technology.)
- Switching frequency is 10MHz and converter always in continuous-conduction mode.
- P_D (Driver Power) is sum of P_{GC} (Gate Charge) and P_{ST} (Shoot Through).
- No metal resistance is added to drivers, so P_{ST} scales slightly faster than R_{SW} .
- Based on 4mm², except: TSMC 0.35 μ m HV minimum is 5mm², and TSMC 0.18 μ m minimum is 25mm².

References:

- TSMC 0.18 μ m (MOSIS: T92Y MM NON EPI THK-MTL)
- TSMC 0.35 μ m (MOSIS: V01C MM NON EPI)
- AMI 0.6 μ m (MOSIS: VO1W)